Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/669,177 Examiner	SHEN ET AL. Art Unit		
R. Stephen Dildine	2133		

SEARCHED					
Class	Subclass	Date	Examiner		
714	752, 791 and 794	5/2/2006	RSD		
H03M	13/11	5/3/2006	RSD		
H03M	13/13	5/3/2006	RSD		
H03M	13/39	5/3/2006	RSD		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
,	DATE	EXMR		
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB (see Search History printout)	5/3/2006	RSD		
IEEEXplore	5/3/2006	RSD		
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Inventors' name search	5/3/200	6 RSD		